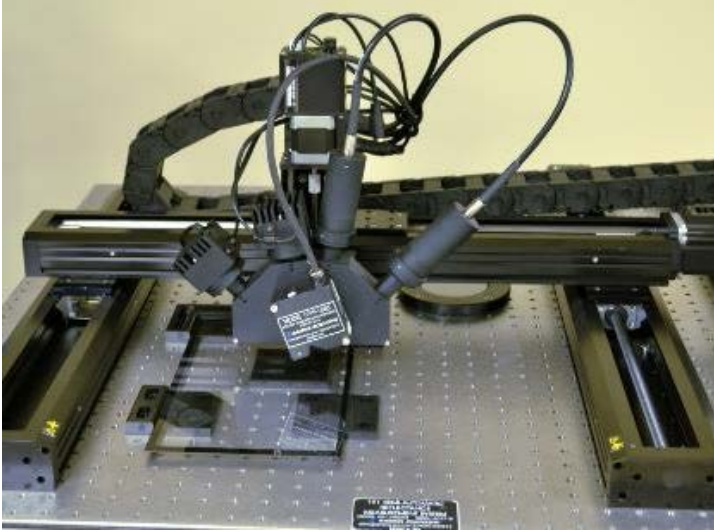


## GS-191SA-1045 Semi-Auto Reflectance Measurement System



The GS-191SA-1045 is a manually loaded gonio-reflectance measurement system that automatically captures complete spectral & colorimetric properties for coated glass, polished substrates or diffuse surfaces at 0° and 45° angle of incidence simultaneously, without requiring second-surface masking. Substrates as thin as 500  $\mu\text{m}$  can be tested with typical scan times of 200 msec per measurement point.

Based on high precision spectroradiometric instrumentation, proprietary measurement techniques and expertise in low-light measurement technology developed by Gamma Scientific, the product range features industry-leading accuracy, repeatability and throughput, including both refractive index determination and thin film coating thickness.

## Highly Accurate & Repeatable Reflection Measurements

- Nondestructively capture complete spectral and colorimetric properties with scan times as short as 200 msec per measurement point
- Isolated first-surface measurement of thin glass substrates down to 500  $\mu\text{m}$  in thickness without requiring second-surface masking
- Measure total reflectance or isolate internal optical interfaces
- Test capability for diffuse or specular surfaces
- Programmable, multi-location measurement, pass/fail criteria settings and binning capabilities
- Configuration options including handheld, semi-automatic and fully automatic rotary systems with robotic loading

### Key Application Areas

- Anti-reflectance coating characterization
- Flat-panel display glass testing
- Touchscreen display glass testing
- Optical filter / lens testing
- Pyrolytic glass coating test & characterization
- Flat panel displays, photovoltaic coatings, low-E architectural coatings, paint samples, diffuse plastics

In addition to our exceptional technical and functional capabilities, Gamma Scientific is ISO/IEC 17025 accredited by NVLAP (NVLAP lab code 200823-0).

## Optical Specifications

191 Optical Head (Optional Geometries of 0° and 20°)	10 Degree Angle of Incidence	45 Degree Angle of Incidence
Measurement Time	First surface specular reflection	First surface specular reflection
Sample Types	Glass	Glass
Illumination Angle	10°	45°
Viewing Angle	10°	45°
Maximum Sample Thickness (first-surface reflectance only)	0.5 mm (transparent samples)	0.25 mm (transparent samples)
Maximum Sample Thickness	6 mm	6 mm
Maximum Sample Size	400 mm x 350 mm	400 mm x 350 mm
Spectral Range	360 to 830 nm	360 to 830 nm
Illumination Spot Size (sample area)	1 mm x 10 $\mu$ m	1 mm x 10 $\mu$ m
Measurement Speed (typical)	< 1500 msec	< 1500 msec
Calibration Reference Standard	Integral BK-7 polished glass	Integral BK-7 polished glass
Spectral Reflectance	$\pm 0.5\%$	$\pm 0.5\%$
Tristimulus (CIE 1931 X,Y,Z)	$\pm 0.05$	$\pm 0.10$
Chromaticity (CIE 1931 x,y)	$\pm 0.005$	$\pm 0.005$
LAB Color (CIE 1976 L*, a*, b*)	L $\pm 2.0$ a*, b* $\pm 0.8$	L $\pm 2.0$ a*, b* $\pm 0.8$
Average Reflectance	$\pm 0.2$	$\pm 0.2$

## System Specifications

191 Optical Head	191F-1045 Dual Angle Optics		
Measurement Program Types (all measured @ 10° & 45° simultaneously)	5 selectable program types, individually configurable for up to 10 different panel sizes: 40-point grid; 25-point grid; 5-point cross, 3-point diagonal; single-point		
Measurement Locations	Position coordinates can be individually set for 10 panel sizes with 1 mm resolution Default grid 10 mm from each edge with equal settings between corner locations		
Cycle Time	Program dependent, each measurement point approximately 1500 msec		
Spectral Data	Reflectance as a function of wavelength		
Colorimetric Data	Tristimulus 1931 X,Y,Z CIE 1976 L*, a*, b*	Tristimulus 1964 X,Y,Z CIE 1976 L*, u*, v*	CIE 1931 x,y
System Dimensions	1.25 meters H x 1.0 meters W x 1.0 meters D    Weight 300 kg		
Operating Ranges	Ambient Temperature 0 to 35°C      Relative Humidity < 90% non-condensing		

Specifications are subject to change without notice.

Optional configurations include handheld devices and fully automatic systems with robotic loading. Custom measurement angle of incidence is also available on request.

